

Supporting information for

Structural insight into an atomic layer deposition (ALD) grown Al₂O₃ layer on Ni/SiO₂: impact on catalytic activity and stability in dry reforming of methane

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Table S1. The coordination^a of Al sites in Al (0.4 nm)-Ni/SiO₂ and Al (4.0 nm)-Ni/SiO₂ after calcination and NH₃-treatment, and the distribution of Al₂O₃ and amorphous aluminosilicate (AAS) phase^b.

Catalyst	Treatment	Al coordination ^a			Al ₂ O ₃		AAS			Al content ^c [mmol/g]	
		Al ^{IV}	Al ^V	Al ^{VI}	Al ^{IV}	Al ^{VI}	Al ^{IV}	Al ^V	Al ^{VI}	Al ₂ O ₃	AAS
γ -Al ₂ O ₃	Calcined	28	3	69	28	69	-	-	-	100	-
	NH ₃ -treated	28	3	69							
Al (0.4 nm)- Ni/SiO ₂	Calcined	22	36	42	5	11	18	36	31	6 (16)	34 (84)
	NH ₃ -treated	48	41	11							
Al (4.0 nm)- Ni/SiO ₂	Calcined	35	41	24	10	23	25	41	1	125 (33)	253 (67)
	NH ₃ -treated	39	38	23							

^aThe coordination of Al sites was fitted with the CzSimple model using the DMFit software with the assumption of all Al sites detected by ²⁷Al MAS NMR. ^bThe Al^{IV} and Al^{VI} sites in Al₂O₃ was calculated using the coordination of Al^{VI} sites after NH₃ treatment, whereby a constant 3:7 ratio is available in γ -Al₂O₃ regardless of calcination and NH₃ treatments. The Al^{IV}, Al^V, and Al^{VI} sites in AAS were calculated by the subtraction of Al^{IV} and Al^{VI} in Al₂O₃. ^cAl content in calcined Al (0.4 nm)-Ni/SiO₂ and Al (4.0 nm)-Ni/SiO₂ was quantified by combination of elemental analysis and ²⁷Al NMR with the assumption that all Al species can be detected by ²⁷Al NMR. The parenthesis represented the relative ratio between Al₂O₃ and AAS

Table S2. Ni K-edge XANES-based linear combination fitting (LCF) quantification of NiAl₂O₄ (mol%) for the benchmarks and Al₂O₃ coated Ni-based DRM catalysts after calcination and DRM (10 h of TOS).

Catalyst	Calcination ^a	After DRM ^b
Ni/SiO ₂	0	0
Ni/Al ₂ O ₃	100	10
Al (0.4 nm)-Ni/SiO ₂	0	0
Al (4.0 nm)-Ni/SiO ₂	30	0
Al (4.0 nm)-Ni/Al ₂ O ₃	100	9
Ni/Al (4.0 nm)-SiO ₂	0	0
Ni/Al (4.0 nm)-Al ₂ O ₃	100	10

^aThe benchmark catalysts Ni/SiO₂ and Ni/Al₂O₃ were calcined at 300 °C, while the ALD Al₂O₃-coated Ni catalysts were calcined at 800 °C. ^bThe catalysts were completely reduced to metallic Ni⁰ at 400–800 °C under 10 vol.% H₂/N₂ prior to DRM tests. The amount of NiAl₂O₄ was quantified after 10 h TOS under DRM conditions at 700 °C.

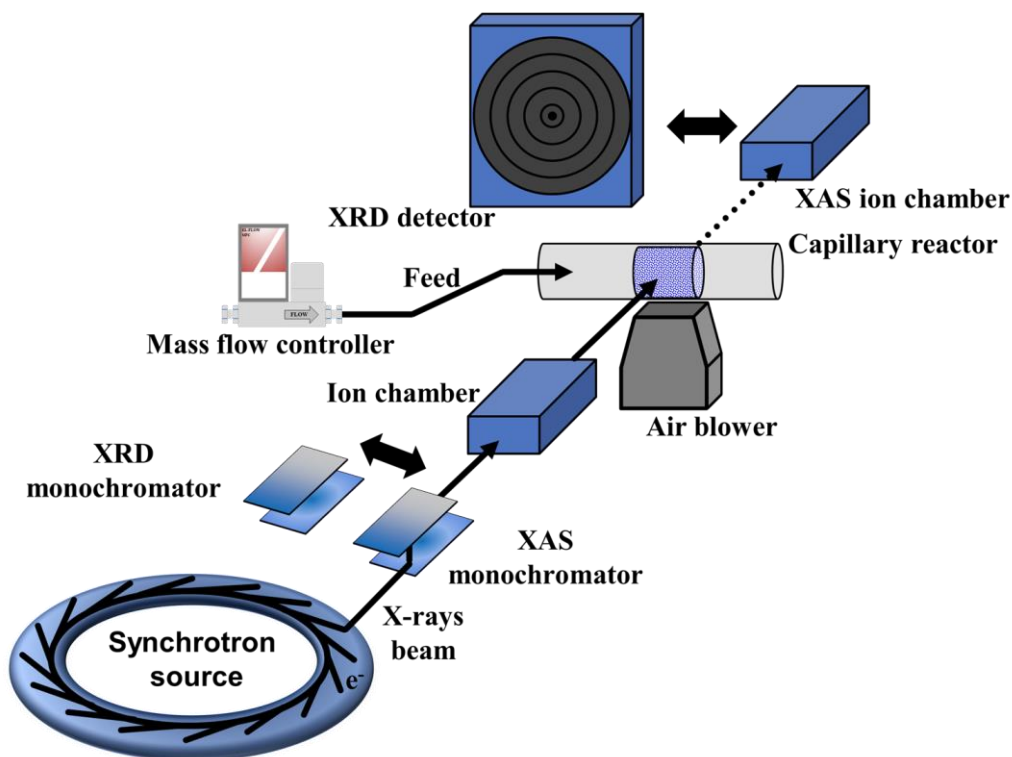


Figure S1. Schematic of the experimental setup for combined *in situ* XAS-XRD measurements BM31 beamline, SNBL at ESRF.

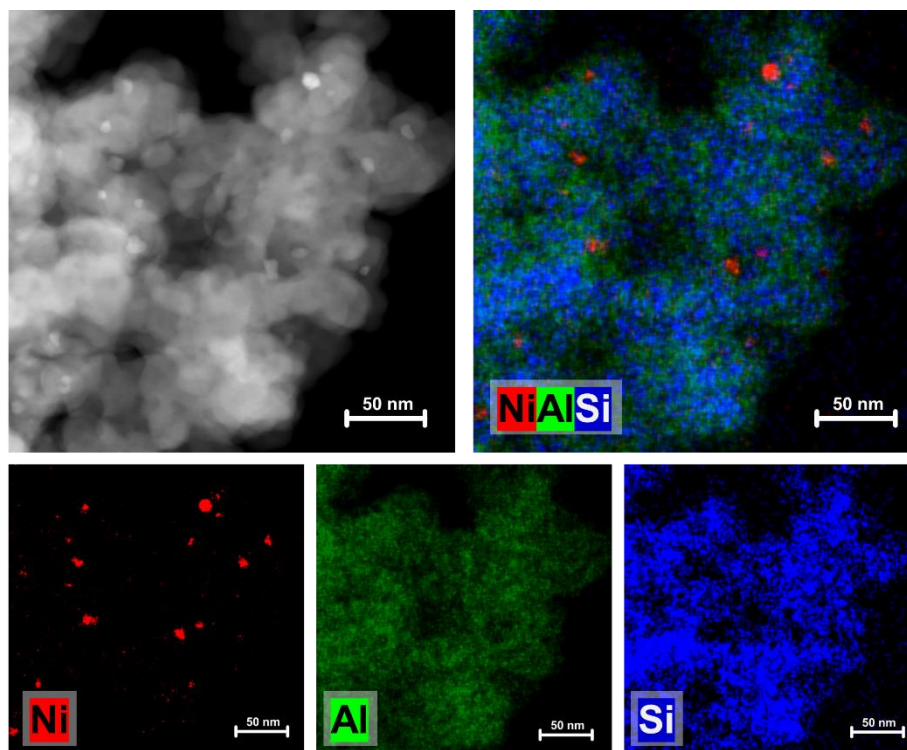


Figure S2. HAADF STEM with EDX analysis of Al (4.0 nm)-Ni/SiO₂ calcined at 800 °C

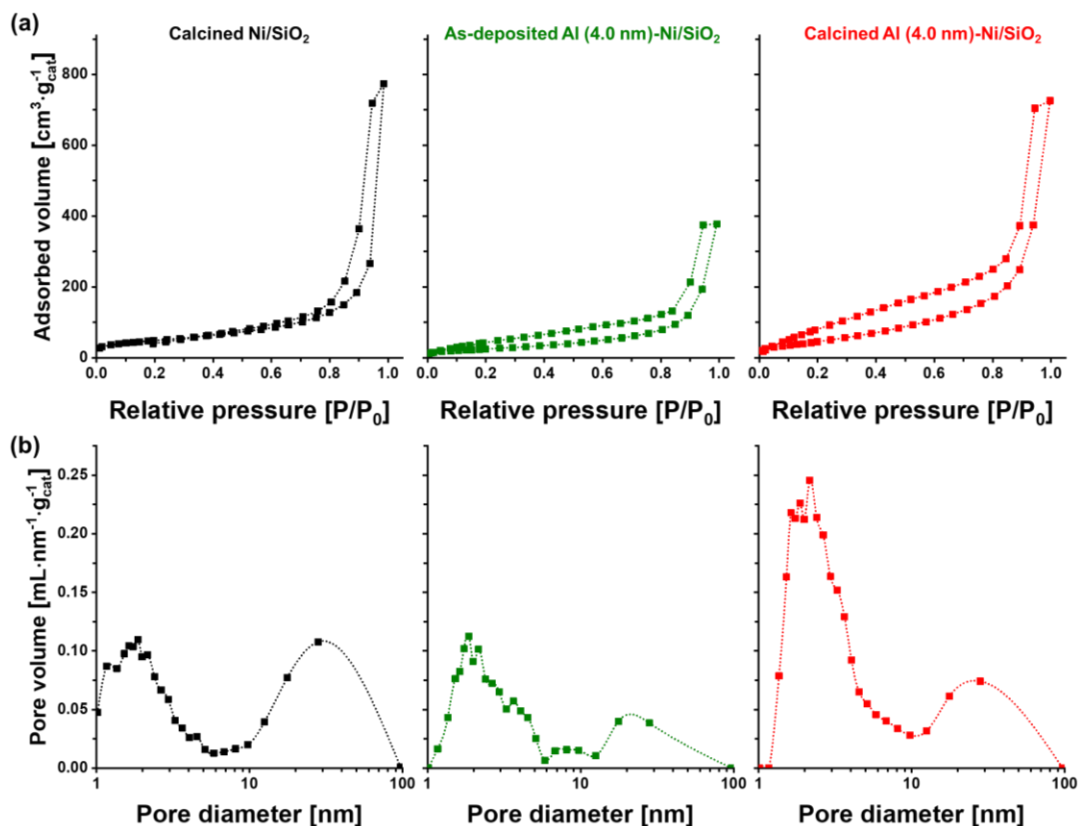


Figure S3. (a) N₂ isotherm and (b) BJH pore size of calcined Ni/SiO₂, as-deposited Al (4.0 nm)-Ni/SiO₂, and calcined Al (4.0 nm)-Ni/SiO₂.

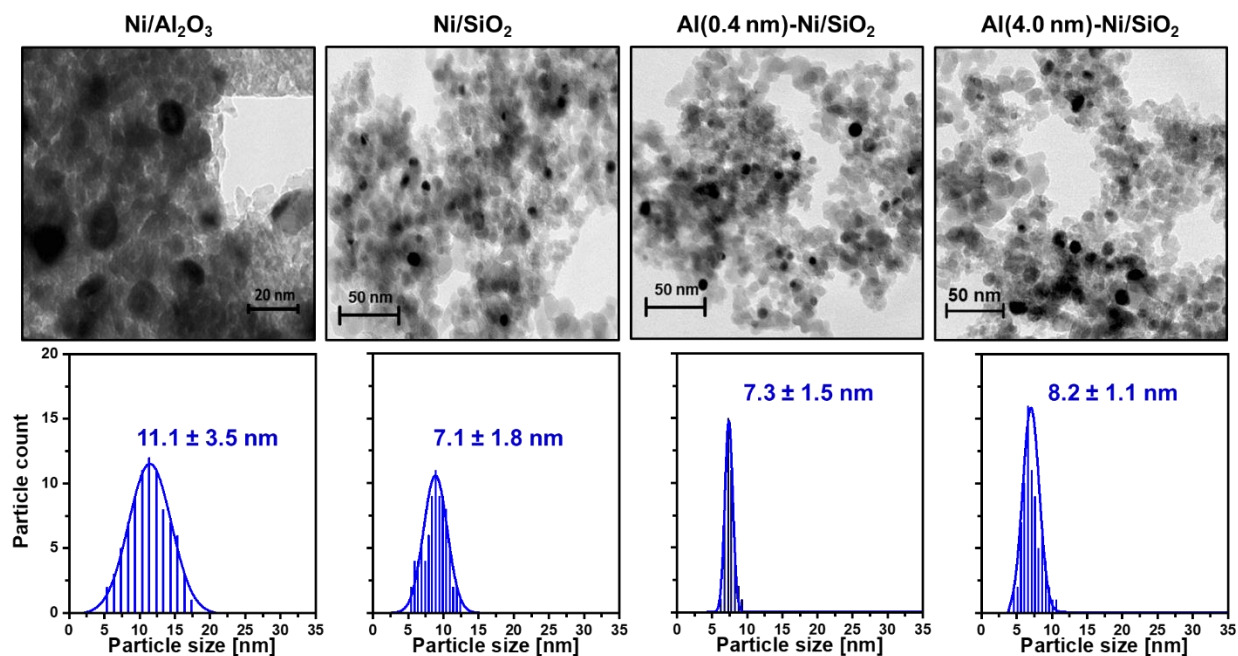


Figure S4. TEM images and particle size distribution of reduced Ni/Al₂O₃, Ni/SiO₂, Al (0.4 nm)-Ni/SiO₂, and Al (4.0 nm)-Ni/SiO₂.

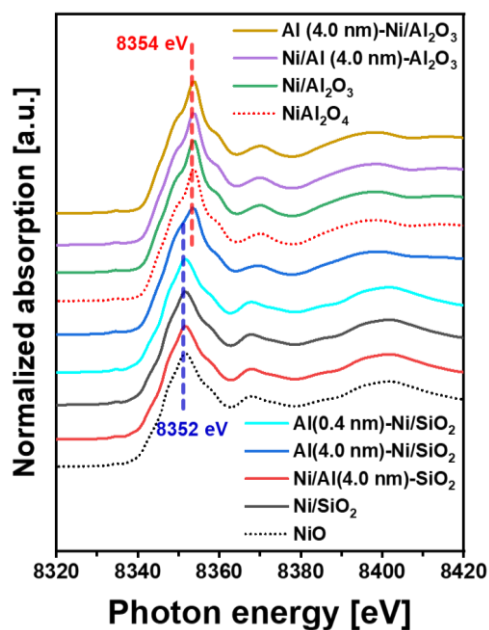


Figure S5. Ni K-edge XANES spectra for calcined Ni/SiO₂, Ni/Al₂O₄, Al (4.0 nm)-Ni/SiO₂, Ni/Al (4.0 nm)-SiO₂, Al (4.0 nm)-Ni/Al₂O₃, and Ni/Al (4.0 nm)-Al₂O₃. NiO and NiAl₂O₄ references plotted for comparison.

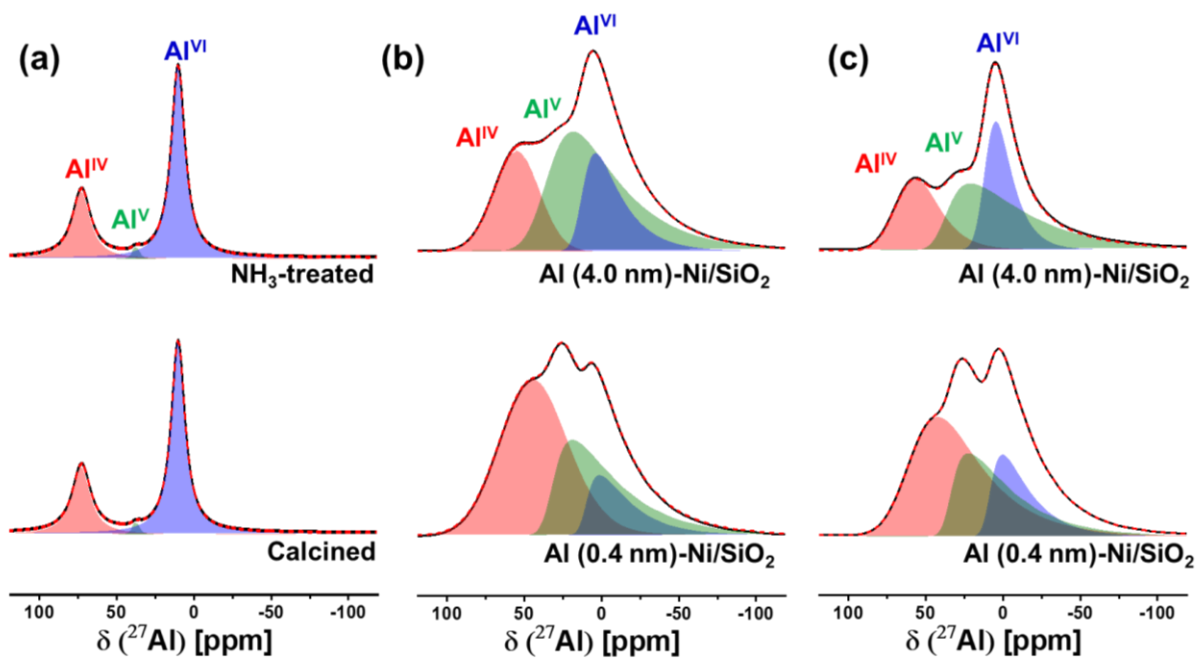


Figure S6. Solid-state ²⁷Al NMR spectra of (a) γ -Al₂O₃ after calcination and NH₃-treatment, and Al (0.4 nm)-Ni/SiO₂ and Al (4.0 nm)-Ni/SiO₂ after (b) NH₃ adsorption and (c) reduction.

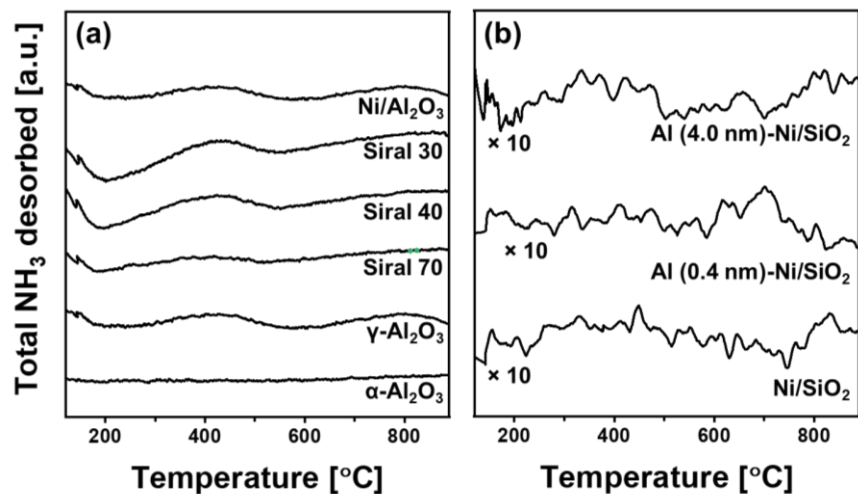


Figure S7. NH_3 -TPD profile of (a) reference and (b) calcined materials.

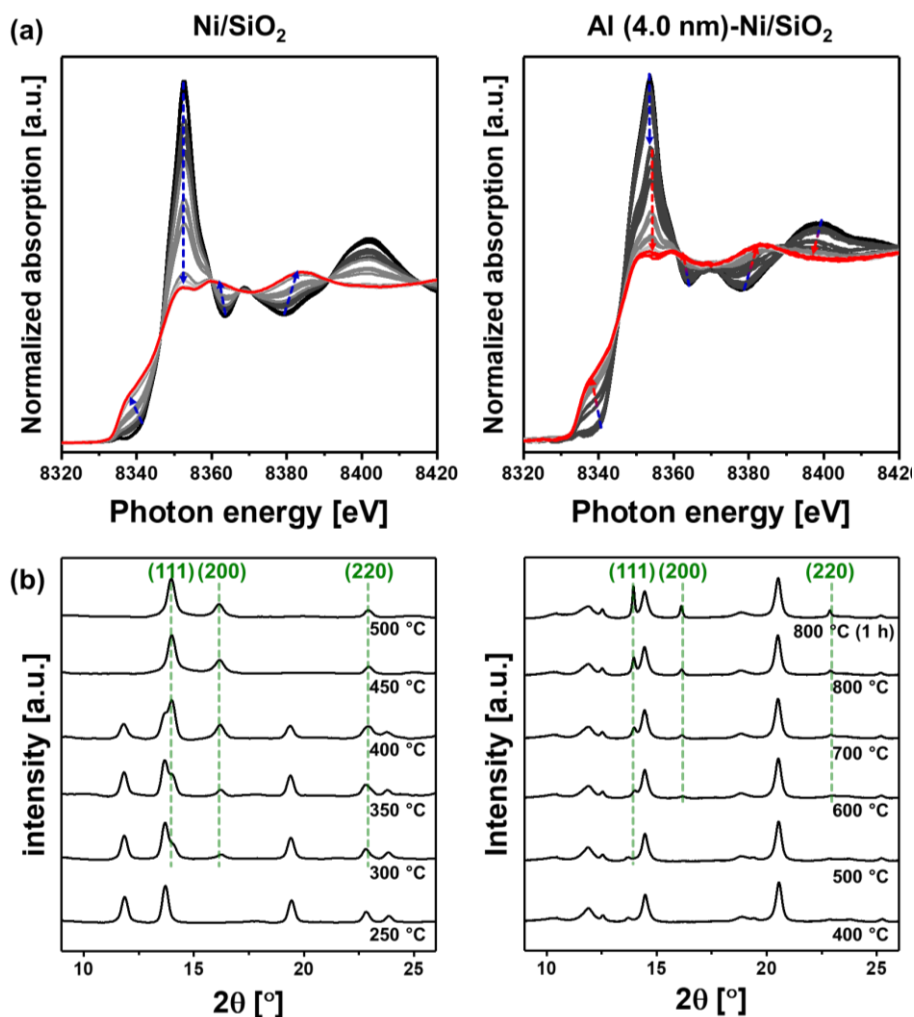


Figure S8. Combined (a) *in situ* Ni K-edge XANES and (b) *in situ* XRD of calcined Ni/SiO_2 and calcined $\text{Al (4.0 nm)-Ni}/\text{SiO}_2$ during reduction. The arrows in (a) indicate the change of XANES upon reduction. The dashed line in (b) represents (111), (200) and (222) Bragg reflections of Ni.

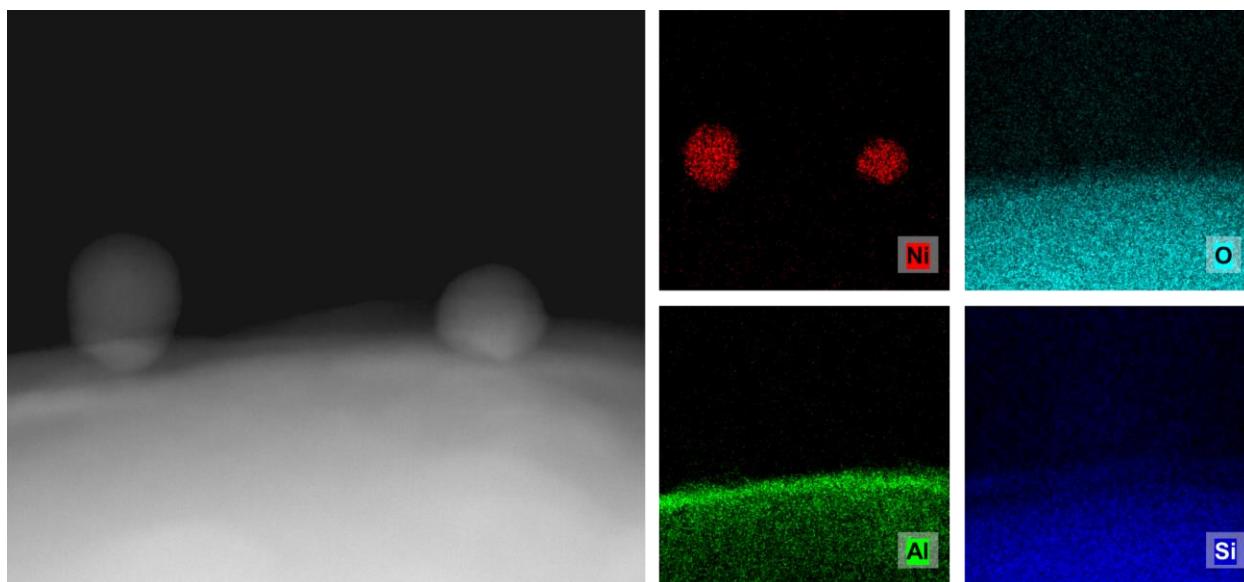


Figure S9. HAADF-STEM images with EDX mapping for reduced Al (4.0 nm)-Ni/SiO₂.

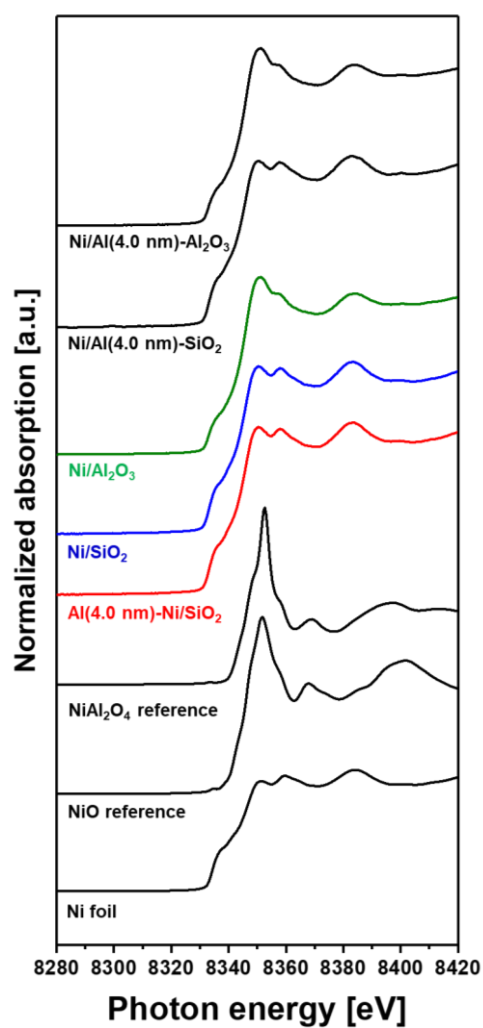


Figure S10. *Ex situ* Ni K-edge XANES for spent catalysts after 10 h of DRM and references.